


<b>Search Notes</b>  	<b>Application/Control No.</b>  10067036	<b>Applicant(s)/Patent Under Reexamination</b>  KATARIA, SEEMA
	<b>Examiner</b>  Nguyen-Ba, Hoang-Vu A	<b>Art Unit</b>  2623

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
725/147, 143, 144, 151, 137, 138, 139, 114; 348/552, 553, 554, 555, 556, 558; H04N 5/46; H04N 3/27 - text search only	4/24/07	HAN
QEM (Koenig, Beliveau, Vu, Saltarelli)	4/24/07	HAN
David Harvey consulted	4/25/07	HAN
Victor Kostak consulted	4/26/07	HAN
Non Patent Literature Search -- Google	4/24/07	HAN
QEM -- Salce, Beliveau	12/12/07	HAN
345/\$; 348/\$	12/12/07	HAN
Non Patent Literature Search -- Google	12/12/07	HAN
Japanese Patent Database --- PAJ	12/12/07	HAN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner